



# UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE  
United States Patent and Trademark Office  
Address: COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, Virginia 22313-1450  
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/757,175	01/09/2001	Pang-Chia Lu	10234-2	1308
23455	7590	06/27/2006	EXAMINER	
EXXONMOBIL CHEMICAL COMPANY			CHANG, VICTOR S	
5200 BAYWAY DRIVE			ART UNIT	
P.O. BOX 2149			PAPER NUMBER	
BAYTOWN, TX 77522-2149			1771	

DATE MAILED: 06/27/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

**UNITED STATES DEPARTMENT OF COMMERCE****U.S. Patent and Trademark Office**

Address : COMMISSIONER FOR PATENTS

P.O. Box 1450

Alexandria, Virginia 22313-1450

09/757,175

APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION	ATTORNEY DOCKET NO.
---------------------------------	-------------	---	---------------------

EXAMINER
----------

ART UNIT	PAPER
----------	-------

20060620

DATE MAILED:

**Please find below and/or attached an Office communication concerning this application or proceeding.**

**Commissioner for Patents**

In view of the full translation, copies of JAP and Derwent Abstract are no longer needed for the Office action mailed 6/14/2006, and have not been provided in the PTO-892 form. It is noted that in the heading of section 5 of the Office action the relied upon reference JP 04-367449 has been properly switched to the full English translation, instead of Patent Abstract of Japan (JAP) and Derwent Abstract. For the headings in sections 6 and 7, however, the changes were inadvertently not made. Nevertheless, the body of each of sections 6 and 7 has clearly indicated that the same teachings of the full English translation are relied upon, and the Examiner wish to clarify that in fact the same reference (translation) are relied upon, the JAP and Derwent Abstract should be ignored. If Applicants have further questions about the references being applied, please contact the Examiner for an interview.

*Vue-Chaif*  
*Examiner*  
*AU 1771*